

O I P E
APR 03 2003
PATENT & TRADEMARK

#2/a
PATENT
6/1/03

Docket No.: 50006-128

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Makoto NAGATA, et al.

Serial No.: 09/977,994

Group Art Unit: 2857

Filed: October 17, 2001

Examiner: Jeffrey R. West

For: METHOD AND APPARATUS FOR ANALYZING A SOURCE CURRENT
WAVEFORM IN A SEMICONDUCTOR INTEGRATED CIRCUIT

AMENDMENT

Commissioner for Patents
Washington, DC 20231

Sir:

The following Amendment and Remarks are submitted in response to the Office
Action dated December 3, 2002.

IN THE SPECIFICATION:

Please amend the paragraph beginning at page 1, line 13 as follows:

91
As electronic devices in a large-scale integrated circuit (referred to as "LSI",
hereinafter) have been reduced in the size, digital circuits patterned in the LSI are scaled
out and improved in an operation speed. However, such LSIs and their application
systems generally suffer from degradation in the performance due to the generation of
noises which results from a change in the source current flowing across the LSI circuits
during the operation.

RECEIVED
IPR-9 2003
TECHNOLOGY CENTER 2800